

**A GRAPHICAL USER INTERFACE FOR TESTING INTEGRATED CIRCUITS**

**ABSTRACT**

5 A system that includes a graphical user interface (GUI)  
connected to an input/output device of a computer system and  
one or more test instruments producing a set of electrical  
signals. The system also includes a probe card that has a  
multiple probe needles used for measuring electronic  
10 characteristics of each of the devices on a semiconductor  
wafer. Each device has cells. Each cell has a set of bond  
pads. The system also has a matrix switch and an interface  
conduit electrically connecting the one or more test  
instruments, the computer, the probe card, and the matrix  
15 switch together. The semiconductor wafer is moved so that the  
probe needles measure the electrical characteristics of each  
cell for each device selected for testing.